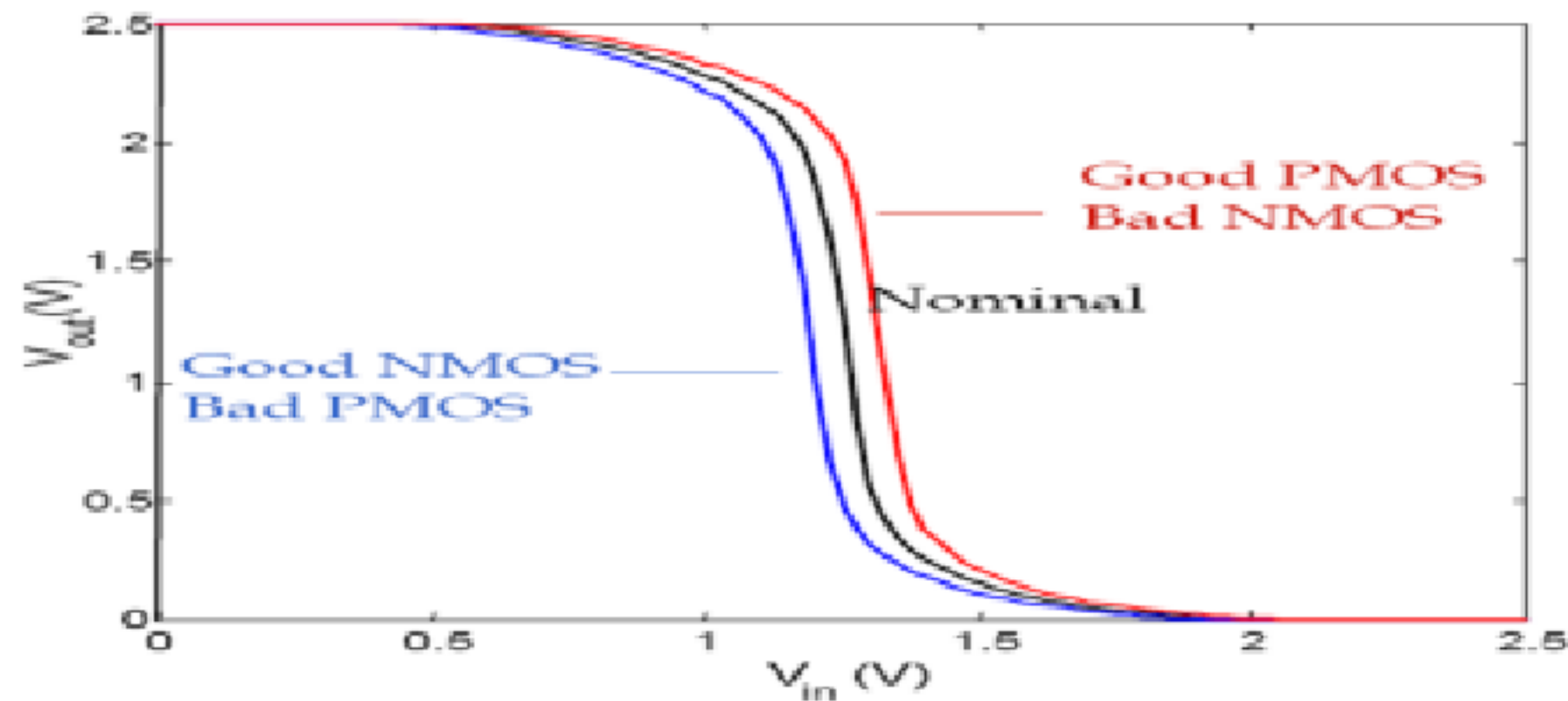


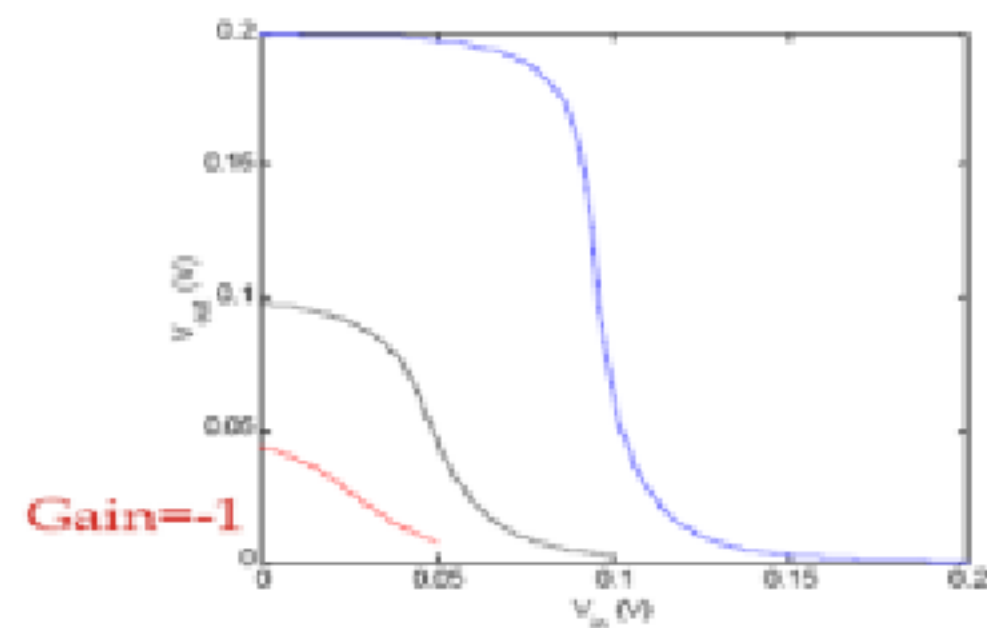
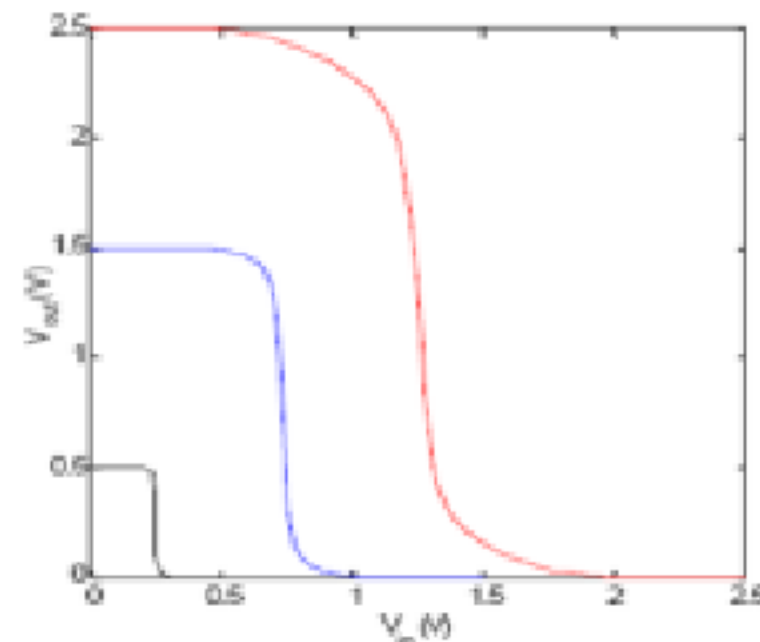
# Impact of Process Variations

- A CMOS inverter remains functional under a **wide range** of operating conditions.
- We showed that variations in device sizes have minor impact on switching threshold.
- This robust behavior, which ensures functionality of the gate over a wide range of conditions, has contributed in a big way to **the popularity of the static CMOS gate.**



# Gain as a function of VDD

- The gain of the inverter actually increases with a reduction of VDD.
- At a VDD = 0.5V, which is just 100mV above V<sub>T</sub> of the transistors. **So why can't we operate all digital circuits at low VDD values?**
- **Yes, you get lower power consumption. But the delay of the gate drastically increases.**
- DC characteristics become very sensitive to variations in device parameters such as V<sub>T</sub> once V<sub>DD</sub> and intrinsic voltages become comparable.
- **~~The signal swing is reduced. Although this is good for internal noise (crosstalk), this is bad for external noise sources that do not scale.~~**





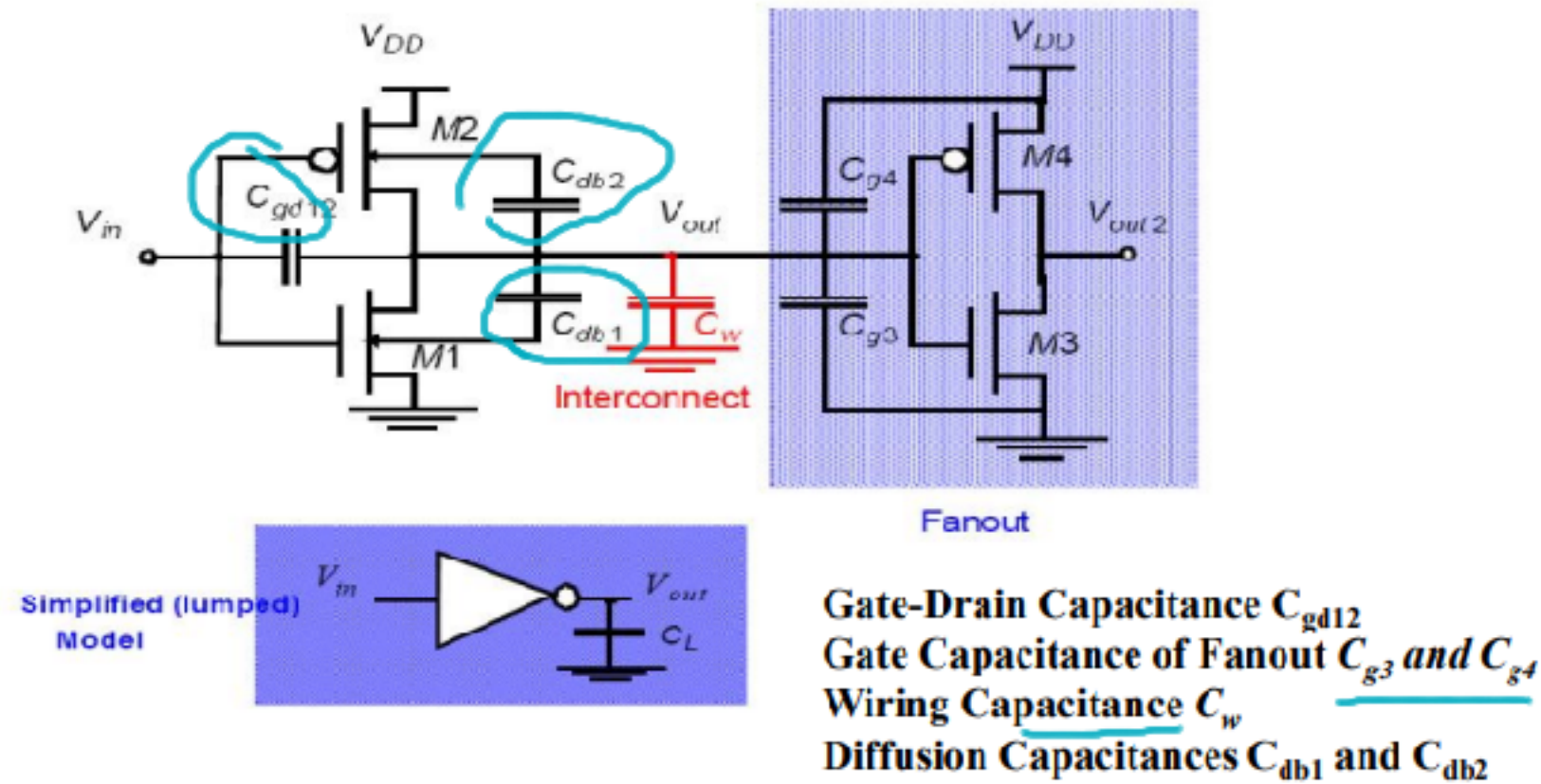
# CMOS Inverter - DC Analysis

SiO<sub>2</sub>

1. High and low outputs =  $V_{DD}$  and Ground. Voltage swing =  $V_{DD}$ .  
(High Noise Margins).
2. Logic Levels are independent of device sizes (ratioless logic).
3. In steady state, a path exists from O/P to  $V_{DD}$  or GND. Thus, **low output impedance**. (Less sensitive to noise).
4. Input resistance is extremely high, since MOS gate draws no dc input current. Steady-state input current ~ zero. An inverter can theoretically drive infinite number of gates and be functionally operational.

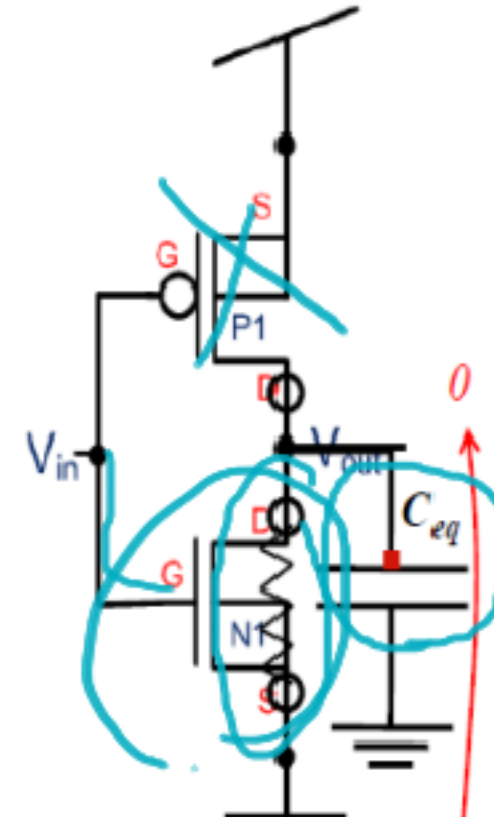


## Computing the Capacitances



## Parasitic Capacitances

- When the input is high, we essentially have closed the top switch and opened the bottom one.
- This creates a **resistive path** from the capacitor to **GND**, and blocks the path from the supply to the output.
- Again we have an **RC network**, though this time we are just **discharging** the capacitance to **GND**.
- We end up with an output equal to **GND**.



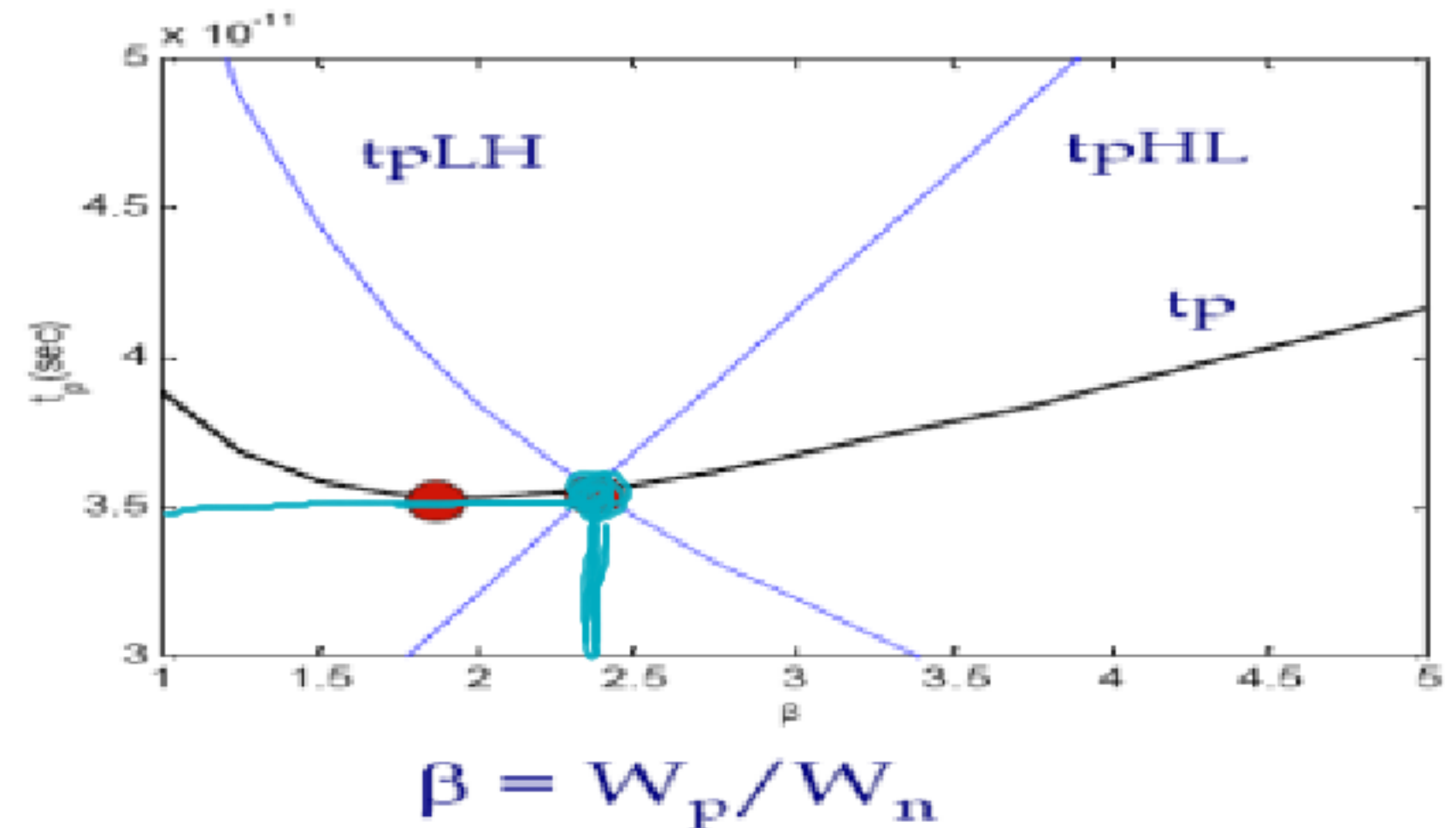
## Parasitic Capacitances

- So we saw that, a switching CMOS inverter **charges and discharges** a parasitic output capacitance.
- During the switching process, we can create a model that will transform the circuit into **a simple RC network**.
- In this way, we can easily derive a first order analysis of the CMOS dynamic operation for **propagation delay** and **power consumption** calculation.



# NMOS/PMOS ratio

**Smaller devices yield faster designs at expense of symmetry and noise margin**

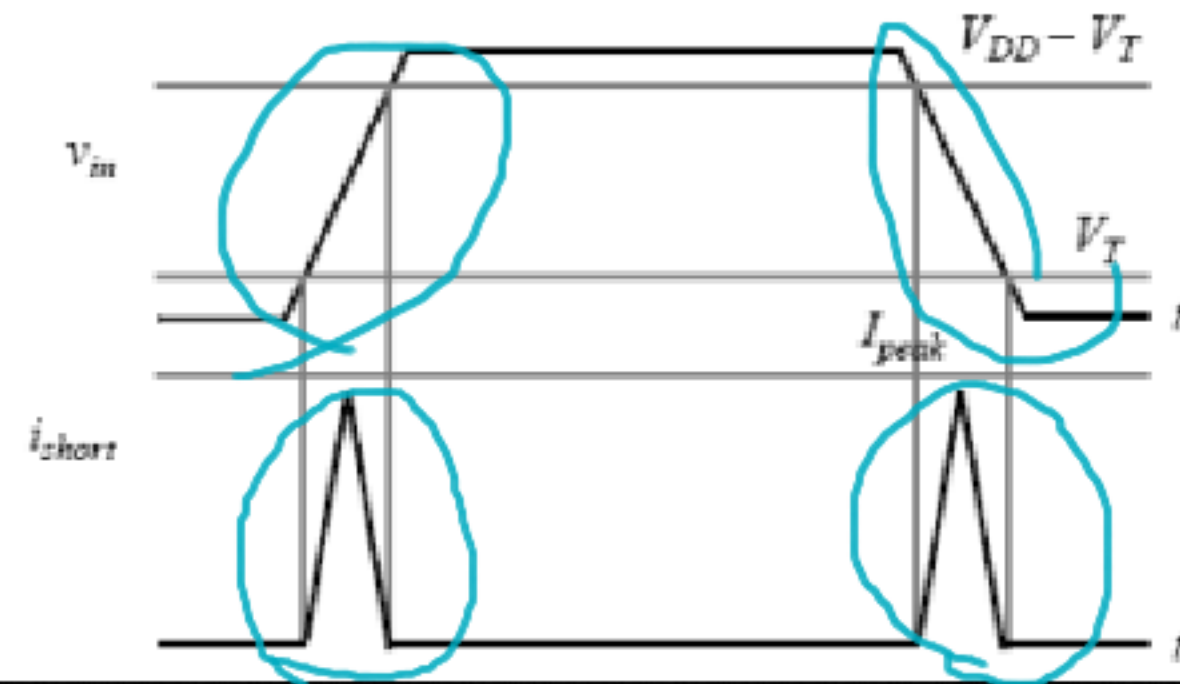
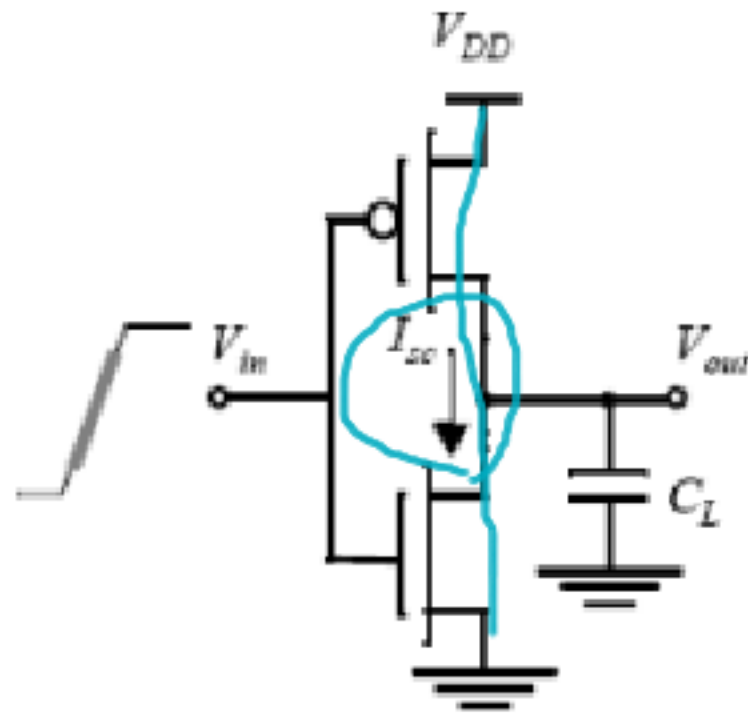


- Increasing the transistor size also raises the diffusion capacitance and hence  $C_L$ .
- In fact, once the intrinsic capacitance (i.e. the diffusion capacitance) starts to dominate the extrinsic load formed by wiring and fan-out, increasing the gate size does not longer help in reducing the delay, and only makes the gate larger in area. This effect is called "**self-loading**".
- In addition, **wide transistors** have a larger **gate capacitance**, which increases the **fan-out** factor of the driving gate and adversely affects its speed.



# Dissipation Due to Direct-Path Currents

- In actual designs, the assumption of the zero rise and fall times of the input wave forms is not correct. The finite slope of the input signal causes a direct current path between  $V_{DD}$  and  $GND$  for a *short period of time during switching*, while the NMOS and the PMOS transistors are conducting simultaneously.

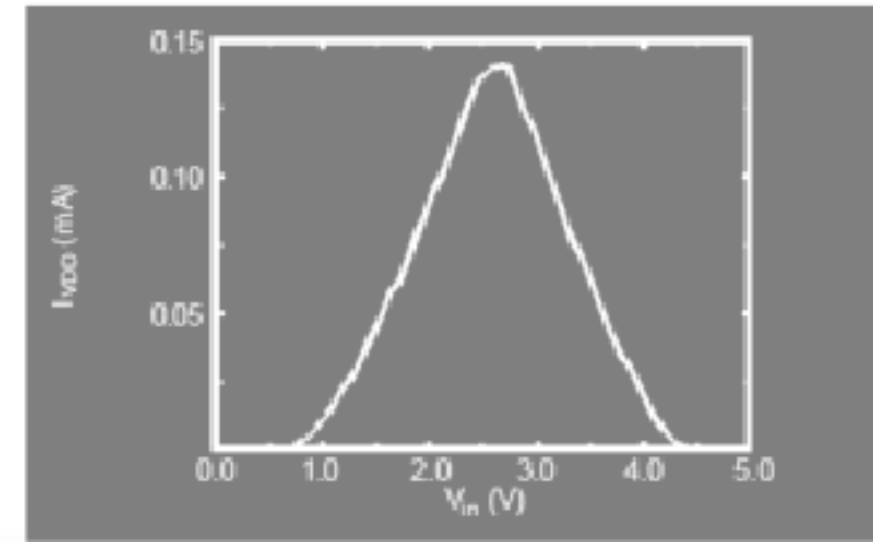
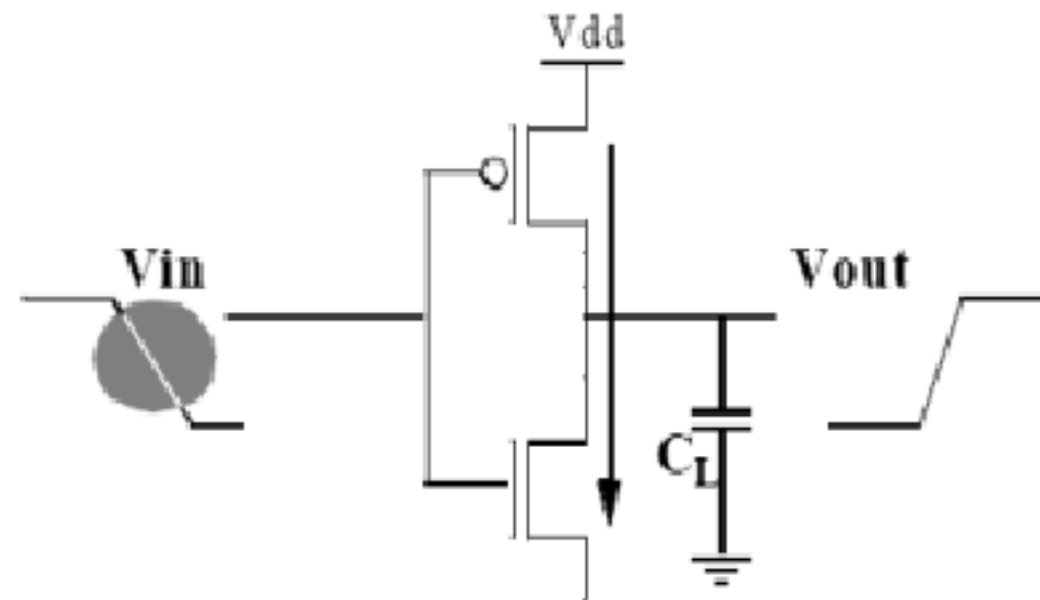




$$t_r = \tau$$

## Short Circuit Currents

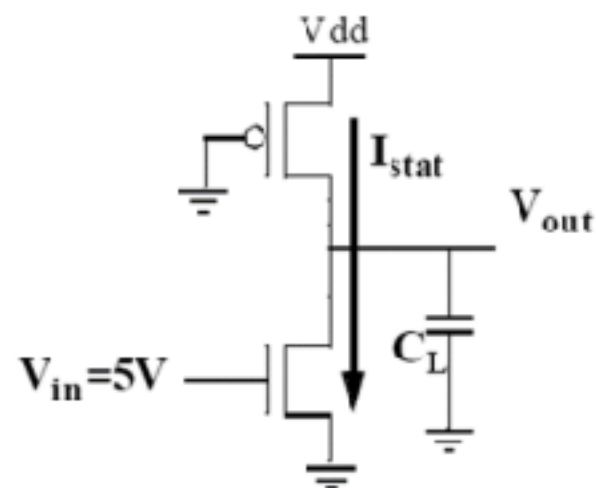
- The power dissipation due to short-circuit currents is minimized by matching the rise/fall times of the input and output signals. At the overall circuit level, this means that rise/fall times of all signals should be kept constant within a range.





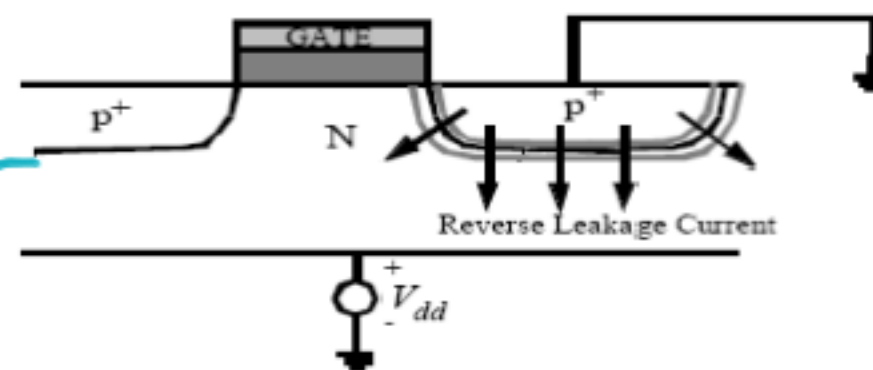
# Static Power Consumption

- Wasted energy ...
- Should be avoided in almost all cases, but could help reducing energy in others (e.g. sense amps)

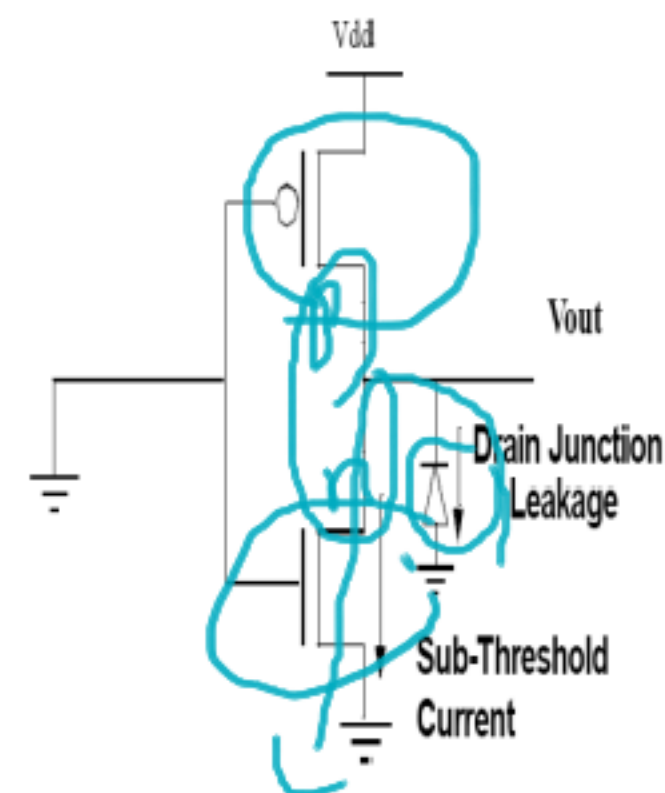


$$P_{stat} = P_{(I_n=1)} \cdot V_{dd} \cdot I_{stat}$$

## Static Consumption - (Leakage)



$$P_{stat} = I_{stat} V_{DD}$$



Sub-threshold current one of most compelling issues in low-energy circuit design!



# Putting It All Together

The total power consumption of the CMOS inverter is now expressed as the sum of its three components:

$$P_{tot} = P_{dyn} + P_{dp} + P_{stat} = (C_L V_{DD}^2 + V_{DD} I_{peak} t_s) f_{0 \rightarrow 1} + V_{DD} I_{leak}$$

- The power dissipation is dominated by the dynamic power consumed in charging and discharging the load capacitor.

It is given by  $P_{0 \rightarrow 1} = C_L V_{DD}^2 f$ .

- The dissipation is proportional to the activity in the network.
- The dissipation due to the direct-path currents occurring during switching can be limited by careful tailoring of the signal slopes.
- The static dissipation can usually be ignored but might become a major factor in the future as a result of subthreshold currents.

## Performance vs. Power Trade-offs.

- Leakage currents cause a rise in static power.
- This is offset by dropping  $V_{DD}$ , which is enabled by reducing  $V_T$  at no cost in performance, and results in quadratic reduction in dynamic power.



# Principles for Power Reduction

- Prime choice: Reduce voltage!
  - Recent years have seen an acceleration in supply voltage reduction
  - Design at very low voltages still open question (0.6 ... 0.9V by 2010!)
- Reduce switching activity
- Reduce physical capacitance
  - Device Sizing



## Impact of Technology Scaling

- *Goals of Technology Scaling*
- Make things cheaper:
  - Want to sell more functions (transistors) per chip for the same money
  - Build same products cheaper, sell the same part for less money
  - Price of a transistor has to be reduced
- But also want to be faster, smaller, lower power.